



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Application Serial No. 09/825,087
Filing Date OCT 23 2003 April 2, 2001
Inventor Cem Basceri et al
Assignee Micron Technology, Inc.
Group Art Unit 2822
Examiner M. Guerrero
Attorney's Docket No. MI22-1483
Title: Mixed Composition Interface Layer and Method of Forming

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OCT 31 2003

TC 1700

INFORMATION DISCLOSURE STATEMENT

References – See Attached Form PTO-1449

The attached form PTO-1449 is submitted in compliance with 37 CFR §1.56. No admission is made regarding whether any of the submitted references is prior art. Copies of the references are attached.

Respectfully submitted,

Dated: 23 Oct 2003

Attorney: James E. Lake
James E. Lake
Reg. No. 44,854

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<p style="text-align: center;">U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE</p> <p style="text-align: center;">LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)</p> <p style="text-align: center;">OCT 23 2003</p> <p style="text-align: center;">PATENT & TRADEMARK OFFICE</p>				ATTY. DOCKET NO. MI22-1483		SERIAL NO. 09/825,087		
				APPLICANT Cem Basceri				
				FILING DATE April 2, 2001		GROUP 1762		
				U.S. PATENT DOCUMENTS				
*Examiner Initial		Document Number	Date	Name		Class	Subclass	Filing Date If Appropriate
	AA							
	AB							
	AC							
	AD							
	AE							
	AF							
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	AH							
	AI							
	AJ							
	AK							
	AL							
FOREIGN PATENT DOCUMENTS								
		Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
	AM							
	AN							
	AO							
	AP							
	AQ							
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)								
	AR	g	Suntola, "Atomic Layer Epitaxy", Handbook of Crystal Growth, Vol. 3, Chapter 14, pps. 602-663.					
	AS	g	Suntola, "Surface Chemistry of Materials Deposition at Atomic Layer Level", Applied Surface Science, vol. 100/101, March 1996, pp. 391-398.					
EXAMINER				DATE CONSIDERED				
<p>*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.</p>								